



CE65H160TOAIF

CoreGaN 650V GaN HEMT

Description

The CE65H160TOAIF Series 650V, 160mΩ gallium nitride (GaN) FETs are normally-off devices.

Coreenergy GaN FETs offer better efficiency through lower gate charge, faster switching speeds, and lower dynamic on-resistance, delivering significant advantages over traditional silicon (Si) devices.

Coreenergy is a leading-edge wide band gap supplier with world-class innovation .

Application

- Adapter
- Renewable energy
- Telecom and data-com
- Servo motors
- Industrial
- Automotive

General Features

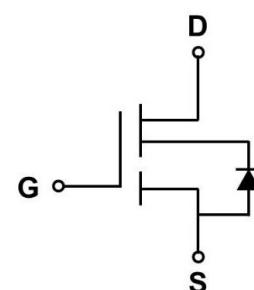
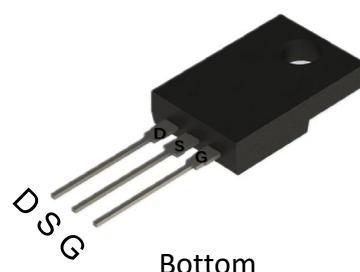
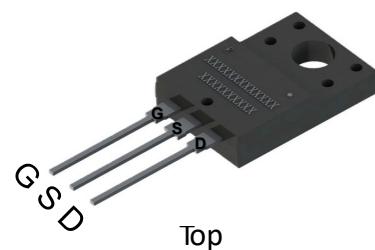
Easy to drive—compatible with standard gate drivers

Low conduction and switching losses

RoHS compliant and Halogen-free

Ordering Information

Part Number	Package	Package Configuration
CE65H160TOAIF	TO220F	Source



Circuit Symbol

Benefits

- Increased efficiency through fast switching
- Increased power density
- Reduced system size and weight

Features

BV_{DSS}	$R_{DS(on)}$	I_{DS}	Q_G
650V	160mΩ	10A	7.4nC



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Absolute Maximum Ratings

$T_c=25^\circ\text{C}$ unless otherwise stated

Symbol	Parameter	Limit value	Unit
V_{DSS}	Drain to source voltage ($T_j = -55^\circ\text{C}$ to 150°C)	650	
$V_{(TR)DSS}$	Drain to source voltage-transient ^a	800	V
V_{GSS}	Gate to source voltage	-20~+20	
I_D	Continuous drain current @ $T_c=25^\circ\text{C}$ ^b	10	A
	Continuous drain current @ $T_c=125^\circ\text{C}$ ^b	4.5	
I_{DM}	Pulse drain current (pulse width: 10μs)	27	A
P_D	Maximum power dissipation @ $T_c=25^\circ\text{C}$	42	W
T_c	Operating temperature	Case	$-55\text{~}150$ $^\circ\text{C}$
T_j		Junction	$-55\text{~}150$ $^\circ\text{C}$
T_s	Storage temperature	-55~150	$^\circ\text{C}$

a. In off-state, spike duty cycle $D<0.01$, spike duration $<1\mu\text{s}$

b. For increased stability at high current operation



CE65H160TOAIF

Thermal Resistance

Symbol	Parameter	Limit value	Unit
R_{\thetaJC}	Junction-to-case	2.95	°C /W



Electrical Parameters

$T_j=25^\circ\text{C}$ unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Forward Device Characteristics						
$V_{(\text{BL})\text{DSS}}$	Drain-source voltage	650	-	-	V	$V_{GS}=0\text{V}$
$V_{GS(\text{th})}$	Gate threshold voltage	3.3	3.9	4.5	V	
$\Delta V_{GS(\text{th})}/T_J$	Gate threshold voltage temperature coefficient	-	-7	-	mV/°C	$V_{DS}=1\text{V}, I_{DS}=1\text{mA}$
$R_{DS(\text{on})}$	Drain-source on-Resistance	-	160	210	mΩ	$V_{GS}=10\text{V}, I_D=1\text{A}, T_J=25^\circ\text{C}$
		-	340	-		$V_{GS}=10\text{V}, I_D=1\text{A}, T_J=150^\circ\text{C}$
I_{DSS}	Drain-to-source leakage current	-	1	10	μA	$V_{DS}=650\text{V}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$
		-	5	100		$V_{DS}=650\text{V}, V_{GS}=0\text{V}, T_J=150^\circ\text{C}$
I_{GSS}	Gate-to-source forward leakage current	-	-	± 100	nA	$V_{GS}=\pm 20\text{V}$
C_{ISS}	Input capacitance	-	330	-		
C_{OSS}	Output capacitance	-	25	-	pF	$V_{GS}=0\text{V}, V_{DS}=400\text{V}, f=1\text{MHz}$
C_{RSS}	Reverse capacitance	-	1	-		
Q_G	Total gate charge	-	7.4	-		
Q_{GS}	Gate-source charge	-	2.6	-	nC	$V_{DS}=400\text{V}, V_{GS}=0\text{V to } 10\text{V}, I_D=1\text{A}$
Q_{GD}	Gate-drain charge	-	1.8	-		
Q_{OSS}	Output charge	-	34	-	nC	$V_{GS}=0\text{V}, V_{DS}=0\text{V to } 400\text{V}, f=1\text{MHz}$
$t_{D(\text{on})}$	Turn-on delay	-	3.2	-		
t_R	Rise time	-	5.5	-	ns	$V_{DS}=400\text{V}, V_{GS}=0\text{V to } 10\text{V}, I_D=2.1\text{A}, R_{G-on(\text{ext})}=6.8\Omega, R_{G-off(\text{ext})}=2.2\Omega, L=250\mu\text{H}$
$t_{D(\text{off})}$	Turn-off delay	-	7.4	-		
t_F	Fall time	-	27	-		



CE65H160TOAIF

Electrical Parameters

$T_j=25^\circ\text{C}$ unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Reverse Device Characteristics						
V_{SD}	Source-Drain reverse voltage	-	2.5	-	V	$V_{GS}=0\text{V}$, $I_{SD}=10\text{A}$
t_{RR}	Reverse recovery time	-	14	-	ns	
Q_{RR}	Reverse recovery charge	-	6.5	-	nC	$I_F=10\text{A}$, $V_{DD}=400\text{V}$, $dI_F/dt=165\text{A}/\mu\text{s}$

Typical Characteristics

$T_j=25^\circ\text{C}$ unless otherwise stated

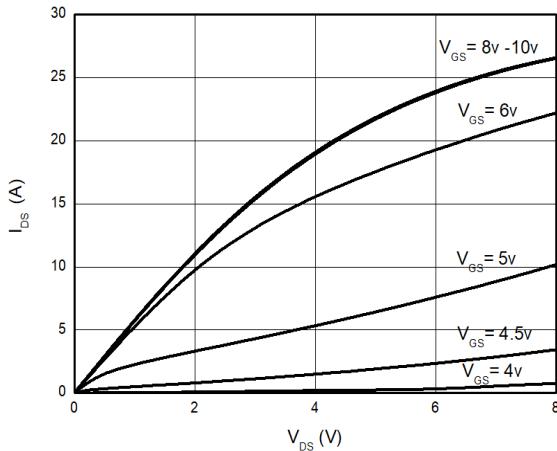


Figure 1. Typical Output Characteristics $T_j=25^\circ\text{C}$

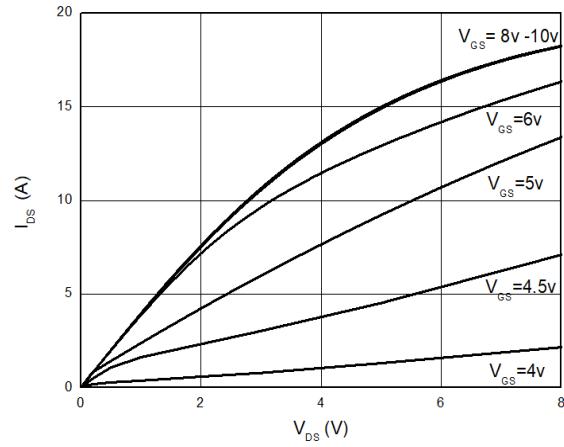


Figure 2. Typical Output Characteristics $T_j=125^\circ\text{C}$

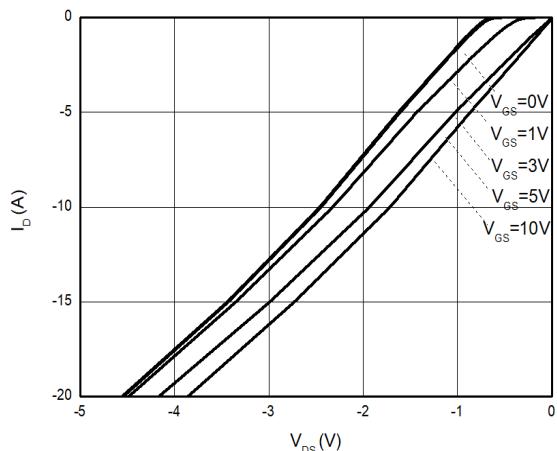


Figure 3. Channel Reverse Characteristics $T_j=25^\circ\text{C}$

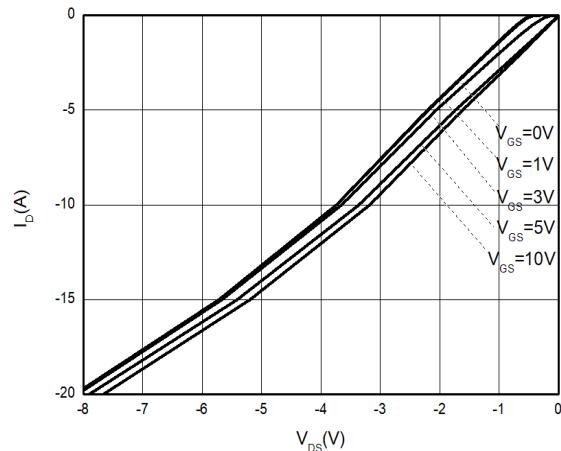


Figure 4. Channel Reverse Characteristics $T_j=125^\circ\text{C}$



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Typical Characteristics

$T_j=25^\circ\text{C}$ unless otherwise stated

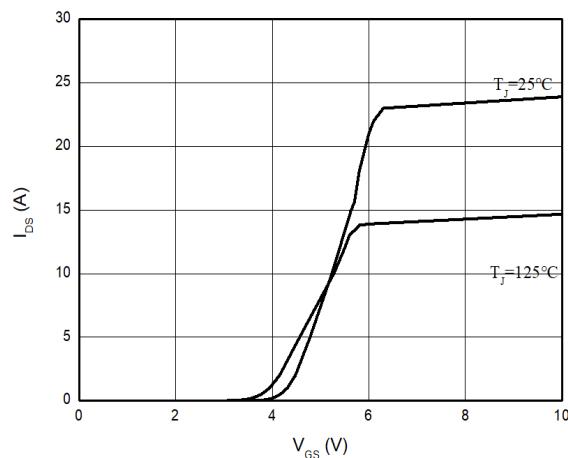


Figure 5. Typical Transfer Characteristics ($V_{DS}=10\text{V}$)

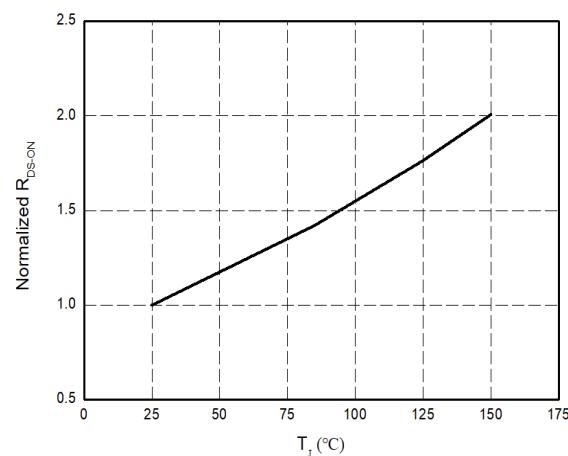


Figure 6. Normalized On-resistance

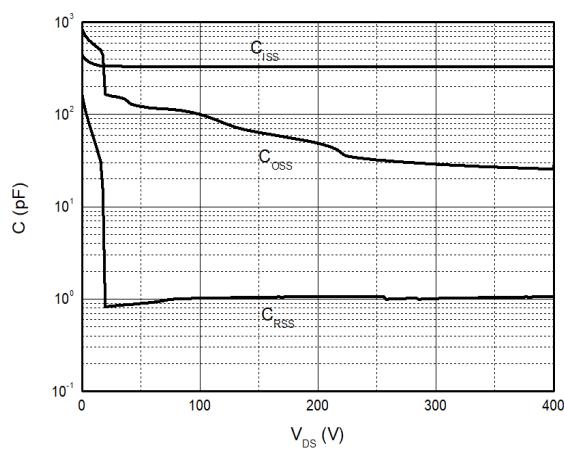


Figure 7. Typical Capacitance ($f=1\text{MHz}$)

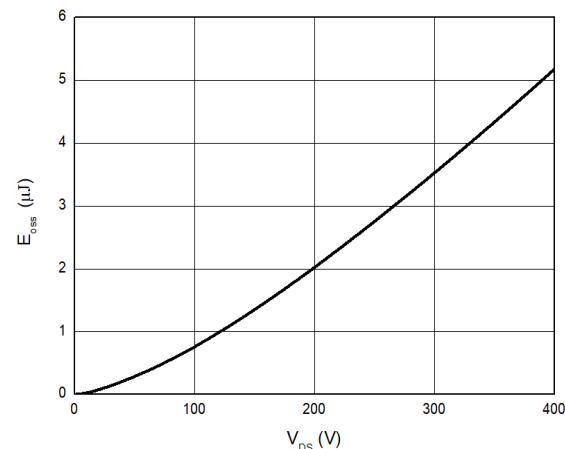


Figure 8. Typical C_{oss} Stored Energy

Typical Characteristics

$T_j = 25^\circ\text{C}$ unless otherwise stated

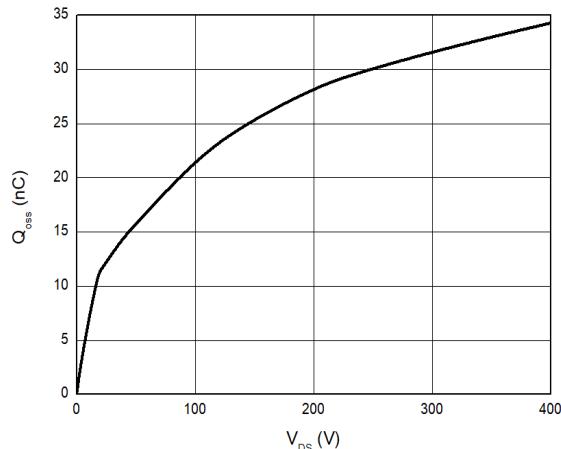


Figure 9. Typical Q_{OSS}

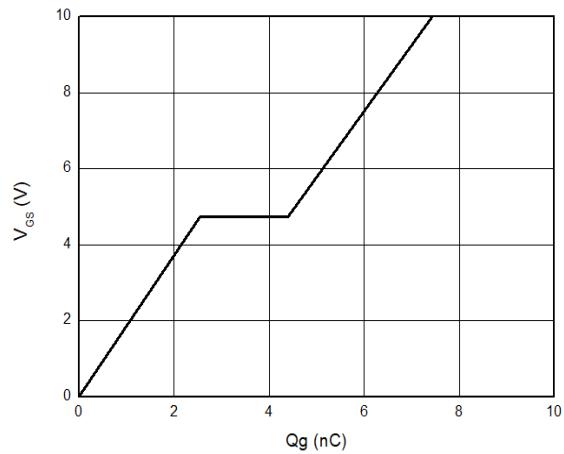


Figure 10. Typical Gate Charge ($V_{DS}=400\text{V}$, $I_D=1\text{A}$)

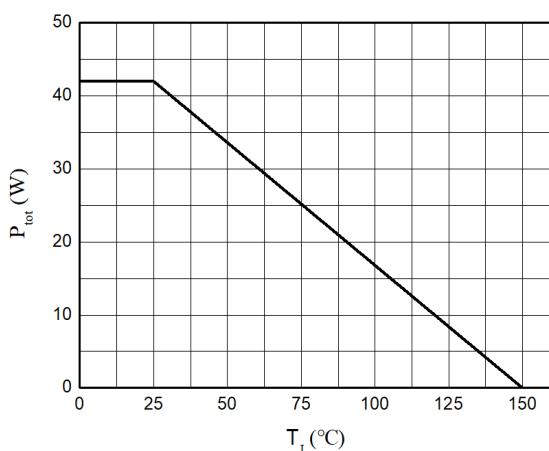


Figure 11. Power Dissipation

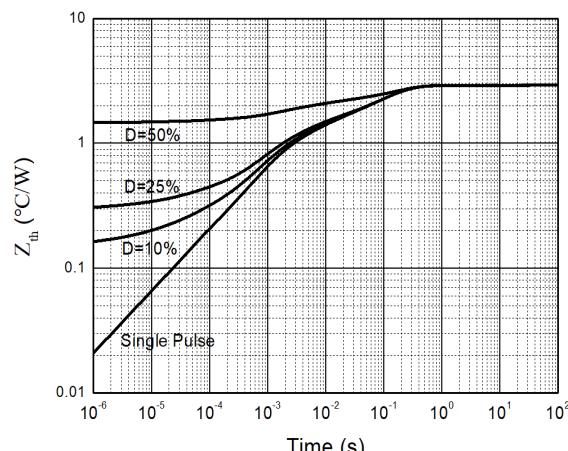


Figure 12. Transient Thermal Resistance

Typical Characteristics

$T_j=25^\circ\text{C}$ unless otherwise stated

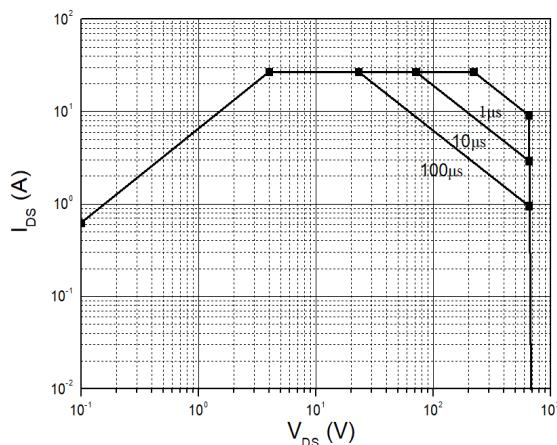


Figure 13. Safe Operating Area $T_c=25^\circ\text{C}$

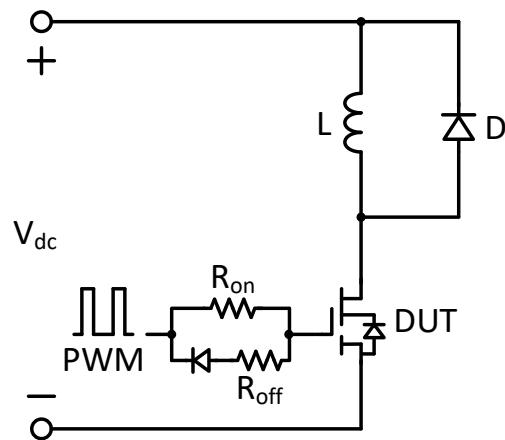


Figure 14. Switching times with inductive load

$V_{DS}=400\text{V}$, $V_{GS}=0\text{V}$ to 10V , $I_D=2.1\text{A}$,
 $R_{G-on(ext)}=6.8\Omega$, $R_{G-off(ext)}=2.2\Omega$, $L=250\mu\text{H}$

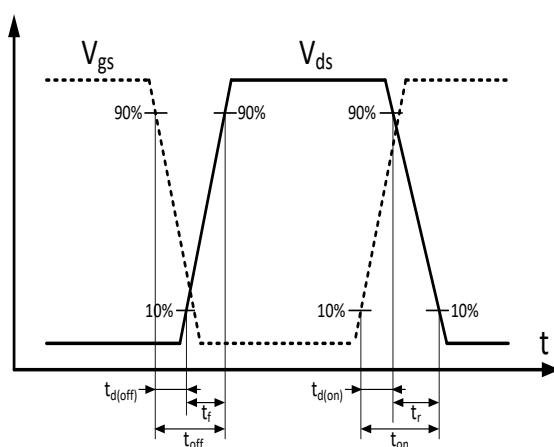
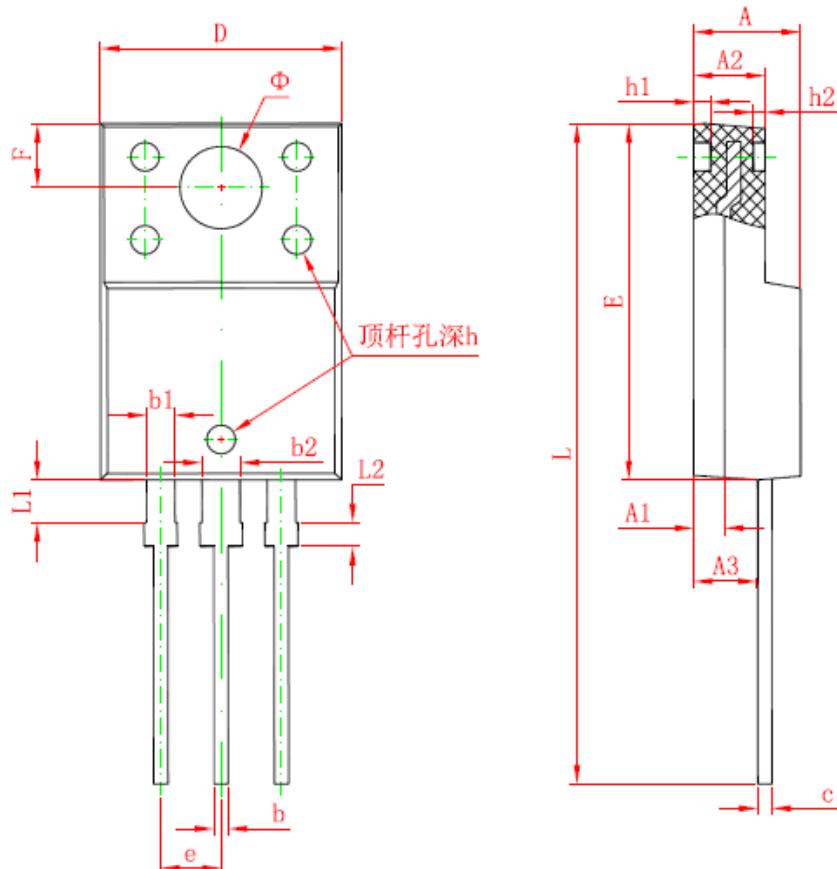


Figure 15. Switching times with waveform

PACKAGE DIMENSIONS

TO220F-3L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.300	4.700	0.169	0.185
A1	1.300	REF.	0.051	REF.
A2	2.800	3.200	0.110	0.126
A3	2.500	2.900	0.098	0.114
b	0.500	0.750	0.020	0.030
b1	1.100	1.350	0.043	0.053
b2	1.500	1.750	0.059	0.069
c	0.500	0.750	0.020	0.030
D	9.960	10.360	0.392	0.408
E	14.800	15.200	0.583	0.598
e	2.540	TYP.	0.100	TYP.
F	2.700	REF.	0.106	REF.
Φ	3.500	REF.	0.138	REF.
h	0.000	0.300	0.000	0.012
h1	0.800	REF.	0.031	REF.
h2	0.500	REF.	0.020	REF.
L	28.000	28.400	1.102	1.118
L1	1.700	1.900	0.067	0.075
L2	0.900	1.100	0.035	0.043



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Revision history

Major changes since the last revision

Revision	Date	Description of changes
1.0	2022-02-28	Initial release
2.0	2023-10-30	Enrich dynamic specification curves
3.0	2023-12-25	Update dynamic parameters